Power MOSFET 30 V, 11.5 A, N-Channel, SO-8

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Includes SyncFET Schottky Diode
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- Synchronous FET for DC-DC Converters
- Low Side Notebook Non-VCORE Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	8.9	Α
Current R _{θJA} (Note 1)		T _A = 70°C		7.2	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	1.39	W
Continuous Drain		T _A = 25°C	I _D	7.1	Α
Current R _{θJA} (Note 2)	Steady	T _A = 70°C		5.7	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.87	W
Continuous Drain		T _A = 25°C	I _D	11.5	Α
Current $R_{\theta JA}$, $t \le 10 s$ (Note 1)		T _A = 70°C		9.2	
Power Dissipation $R_{\theta JA}$, $t \le 10 \text{ s(Note 1)}$		T _A = 25°C	P _D	2.31	W
Pulsed Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \mu s$			I_{DM}	56	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to 150	°C
Source Current (Body Diode)			I _S	3.3	Α
Single Pulse Drain-to–Source Avalanche Energy (T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 11 A_{pk} , L = 1 mH, R_G = 25 Ω)			E _{AS}	60.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	89.9	°C/W
Junction-to-Ambient – $t \le 10 \text{ s (Note 1)}$	$R_{\theta JA}$	54.2	
Junction-to-Foot (Drain)	$R_{\theta JF}$	35.6	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	143	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surfacemounted on FR4 board using 1 sq-in pad, 2 oz Cu.
- 2. Surfacemounted on FR4 board using the minimum recommended pad size.

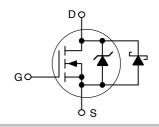


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	12 mΩ @ 10 V	11.5 A
30 V	15 mΩ @ 4.5 V	11.5 A

N-Channel



1 SO-8 CASE 751

STYLE 12

MARKING DIAGRAM/ PIN ASSIGNMENT

Source B B Drain Source B Drain Drain Gate D Drain Top View

4873NF = Device Code A = Assembly Location

Y = Year WW = Work Week • Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4873NFR2G	SO-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS							-
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				10		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$	T _J = 25°C			250	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)	•				•	•	
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.45		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	10 A		9	12	mΩ
		V _{GS} = 4.5 V, I _D =	8.5 A		12	15	1
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	: 10 A		22		S
CHARGES, CAPACITANCES AND GA	ATE RESISTA	NCE	•			•	•
Input Capacitance	C _{iss}				1275	1900	pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz,	V _{DS} = 15 V		345	525	1
Reverse Transfer Capacitance	C _{rss}		•		145	225	1
Total Gate Charge	Q _{G(TOT)}				10.5	16	nC
Threshold Gate Charge	Q _{G(TH)}				1.3		1
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15$	V, I _D = 10 A		3.7	6.0	1
Gate-to-Drain Charge	Q_{GD}	1	•		3.9	6.5	1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15	V, I _D = 10 A		21.4	32	nC
SWITCHING CHARACTERISTICS (No	ote 4)		•			•	•
Turn-On Delay Time	t _{d(on)}				9.8	16	ns
Rise Time	t _r	V _{GS} = 10 V, V _{DS} =	= 15 V.		3.8	7.0	1
Turn-Off Delay Time	t _{d(off)}	I _D = 1.0 A, R _G =	6.0 Ω		22.3	45	1
Fall Time	t _f				14.3	25	1
DRAIN-SOURCE DIODE CHARACTE	RISTICS		•			•	•
Forward Diode Voltage	V_{SD}		$T_J = 25^{\circ}C$		0.55	0.7	V
		V _{GS} = 0 V, I _S = 3.5 A	T _J = 125°C		0.5		1
Reverse Recovery Time	t _{RR}				20	35	ns
Charge Time	t _a	V_{GS} = 0 V, d_{IS}/d_t = 100 A/ μ s, I_S = 10 A			9.5	15	1
Discharge Time	t _b				10.6	20	1
Reverse Recovery Charge	Q _{RR}				9.0	14	nC
PACKAGE PARASITIC VALUES	-				-	-	
Source Inductance	L _S	T _A = 25°C			0.66		nH
Drain Inductance	L _D				0.20		nH
Gate Inductance	L _G				1.5		nH
Gate Resistance	R _G				1.5	3.0	Ω

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

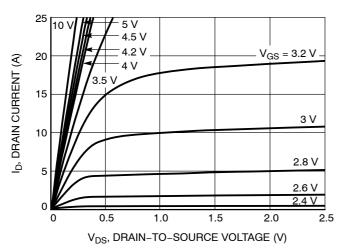


Figure 1. On-Region Characteristics

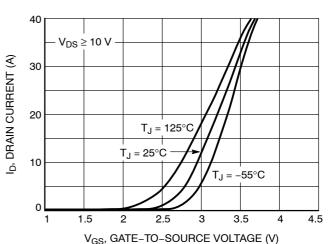


Figure 2. Transfer Characteristics

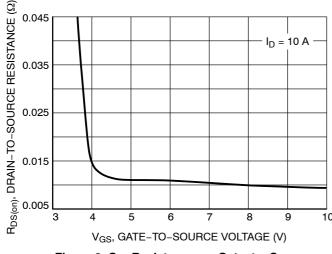


Figure 3. On-Resistance vs. Gate-to-Source Voltage

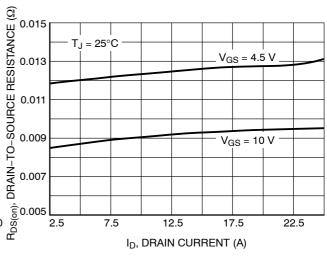


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

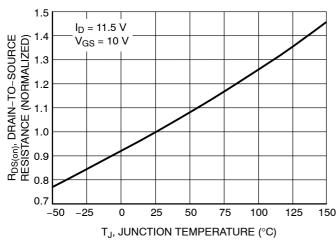


Figure 5. On–Resistance Variation with Temperature

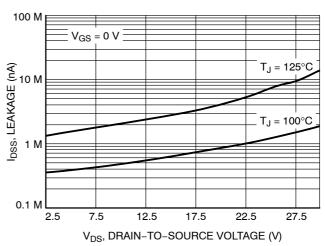


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

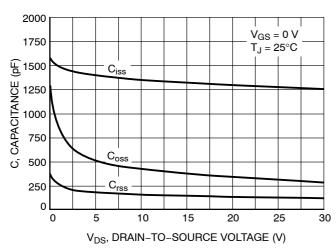


Figure 7. Capacitance Variation

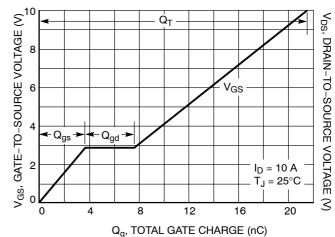


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

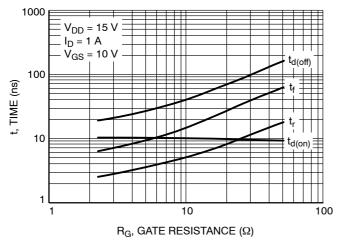


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

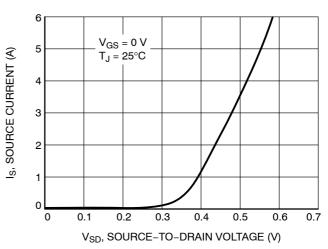


Figure 10. Diode Forward Voltage vs. Current

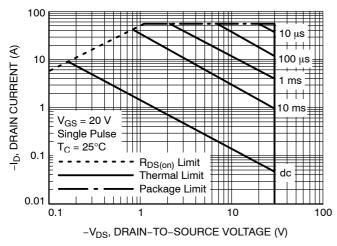


Figure 11. Maximum Rated Forward Biased Safe Operating Area

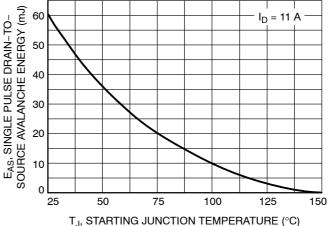


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

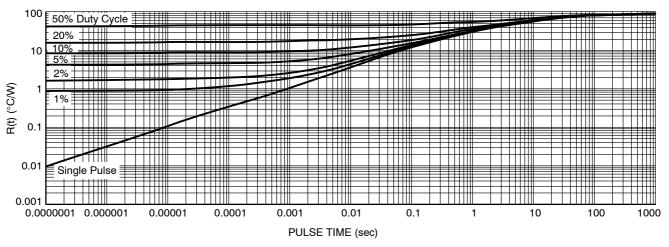
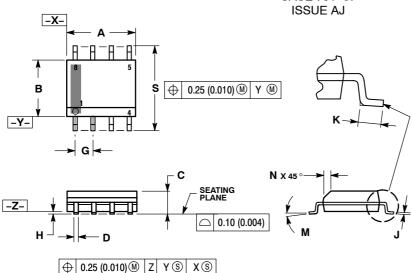


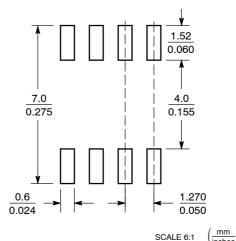
Figure 13. Thermal Response – $R_{\theta JA}$ at Steady State (1 inch sq pad)

PACKAGE DIMENSIONS

SOIC-8 CASE 751-07



SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
C	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27	1.27 BSC		0 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

- STYLE 12: PIN 1. SOURCE
 - SOURCE 3. SOURCE
 - 4 GATE
 - 5. DRAIN
 - DRAIN
 - DRAIN 8. DRAIN

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